

	Type	L #	Hits	Search Text	DBs	Time Stamp	Comments
1	BRS	L1	197	(amorphous or "non-crystalline") same (material or strip or piece or element or band or member) and bias adj3 magnetiz\$5 and (indicat\$3 or sens\$3 or detect\$3 or monitor\$3)	US- PGPUB ; USPAT ; USOCR ; FPRS; EPO; JPO; DERWE NT; IBM_T DB	2006/10/2 5 11:06	
2	IS&R	L2	5	(("5275049") or ("4463610") or ("5982054") or ("5194806") or ("5321985")) . PN.	USPAT	2006/10/2 5 11:11	
3	IS&R	L3	751	(310/26) .CCLS.	USPAT	2006/10/2 5 11:20	
4	IS&R	L4	126	(310/26) .CCLS.	US- PGPUB ; FPRS; EPO; JPO; DERWE NT; IBM_T DB	2006/10/2 5 11:20	

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OR **AND****AND** **AND****AND** **AND****Date of publication of application — e.g.19980401 - 19980405** - **AND****IPC — e.g. D01B7/04 A01C11/02**

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SENSOR.

Publication number: MXPA04012921

Publication date: 2005-07-26

Inventor: CEDELL TORD (SE)

Applicant: COVIAL DEVICE AB (SE)

Classification:

- **International:** G01H11/04; G01P15/08; G01H11/00; G01P15/08;
(IPC1-7): G01B7/24; G01H11/04; G01L1/12; G01P15/11

- **european:** G01H11/04; G01P15/08F

Application number: MX2004PA12921 20041216

Priority number(s): SE20020001927 20020620; WO2003SE00871
20030528

Also published as:

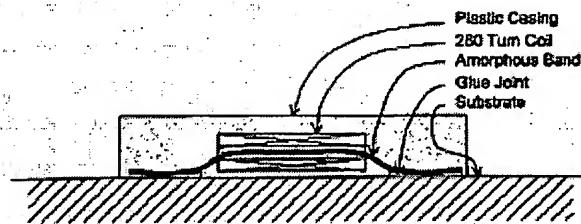
- WO2004001353 (A1)
- US2005242806 (A1)
- EP1514082 (A0)
- CN1662795 (A)
- CA2489171 (A1)

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Abstract of MXPA04012921

The disclosure relates to a method and an apparatus for sensing and indicating permanent state deviations via detection of temporary inner material oscillations in real time in parts of importance for hardware design and construction, within existing production equipment, e.g. machinery, and/or monitoring of previously built-up infrastructure. One or more at least approximately 20 m thick amorphous or nanocrystalline band elements with high permeability and relatively high magnetostriction are applied to a pertinent part, the band element or elements, respectively, being at least partially surrounded by a multi-turn coil, such atomic movements (oscillations) as occur in any optional such state deviation in the part being transferred to the band element/elements. The deviation either gives rise to a clearly measurable and detectable magnetic flow change (dB/dt) in the coil in proportion to said atomic movements, or to a similarly measurable and detectable inductance change in the coil/coils.



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MAGNETIC SENSOR

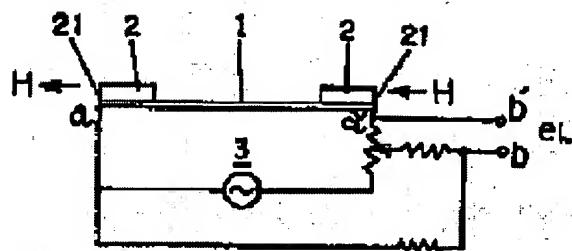
Publication number: JP9145808
Publication date: 1997-06-06
Inventor: MITSUBE MASANORI
Applicant: UCHIHASHI ESTEC CO LTD
Classification:
- International: G01R33/02; G01R33/02; (IPC1-7): G01R33/02
- european:
Application number: JP19950328236 19951121
Priority number(s): JP19950328236 19951121

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Abstract of JP9145808

PROBLEM TO BE SOLVED: To provide a magnetic sensor that can be sufficiently improved in external magnetic field detecting sensitivity only by the simple addition of members in the case of making a current flow to an amorphous magnetic wire and detecting only the voltage part by inductance out of voltage generated by this current to detect the axial external magnetic field of the wire from the change of the detected voltage.

SOLUTION: A current is made to flow to an amorphous magnetic wire 1, and only the voltage part e_L by inductance out of voltage generated by this current is detected to detect the axial external magnetic field H of the wire 1 from the change of the detected voltage. In a magnetic sensor of such constitution, material 2, 2 of high permeability are fitted to a head part of the sensor, or a pair of material of high permeability are provided on a base, and the amorphous magnetic wire is connected between these material of high permeability.



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RESULT LIST

1 result found in the Worldwide database for:

sens* in the title AND **amorphous and coil and bias and magnetization** in the title or abstract
(Results are sorted by date of upload in database)**1 MAGNETIC FIELD SENSOR****Inventor:** YABE SUNAO; OGA SUEYOSHI; (+3)**Applicant:** KAWATETSU TECHNO RES KK**EC:****IPC:** **G01R33/02; G01R33/02;** (IPC1-7): G01R33/02**Publication info:** **JP3092782 - 1991-04-17**

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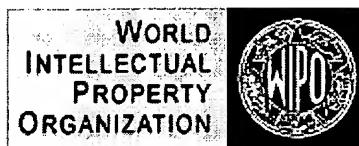
RESULT LIST

0 results found in the Worldwide database for:

amorphous and sens* in the title **AND detect* and magnetic and flow** in the title or abstract

(Results are sorted by date of upload in database)

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Home > IP Services > PatentScope > Patent Search

Results of searching in PCT for:

(indicat* and sens*) and (amorphous or "nano-crystalline") and bias and magnet* and magnetic
near flow near change: 0 records

[\[Search Summary\]](#)

[Refine Search](#)

(indicat* and sens*) and (amorphous or "nano-crystallin

RSS

No records matching your query found in PCT

Search Summary

RSS

indicat* NEAR flow: 444 occurrences in 328 records.

indicat* NEAR change: 594 occurrences in 488 records.

(indicat* NEAR flow AND indicat* NEAR change): 2 records.

sens* NEAR flow: 1702 occurrences in 1028 records.

sens* NEAR change: 597 occurrences in 508 records.

(sens* NEAR flow AND sens* NEAR change): 7 records.

((indicat* NEAR flow AND indicat* NEAR change) AND (sens* NEAR flow AND sens* NEAR change)): 0 records.

amorphous NEAR flow: 5 occurrences in 3 records.

amorphous NEAR change: 10 occurrences in 10 records.

(amorphous NEAR flow AND amorphous NEAR change): 0 records.

nano-crystalline NEAR flow: 0 occurrences in 0 records.

nano-crystalline NEAR change: 0 occurrences in 0 records.

(nano-crystalline NEAR flow AND nano-crystalline NEAR change): 0 records.

((amorphous NEAR flow AND amorphous NEAR change) OR (nano-crystalline NEAR flow AND nano-crystalline NEAR change)): 0 records.

((((indicat* NEAR flow AND indicat* NEAR change) AND (sens* NEAR flow AND sens* NEAR change)) AND ((amorphous NEAR flow AND amorphous NEAR change) OR (nano-crystalline NEAR flow AND nano-crystalline NEAR change))) OR (bias NEAR flow AND bias NEAR change)): 0 records.

bias NEAR flow: 19 occurrences in 16 records.

bias NEAR change: 18 occurrences in 17 records.

(bias NEAR flow AND bias NEAR change): 0 records.

((((indicat* NEAR flow AND indicat* NEAR change) AND (sens* NEAR flow AND sens* NEAR change)) AND ((amorphous NEAR flow AND amorphous NEAR change) OR (nano-crystalline NEAR flow AND nano-crystalline NEAR change))) AND (bias NEAR flow AND bias NEAR change)): 0 records.

magnet* NEAR flow: 307 occurrences in 234 records.

magnet* NEAR change: 262 occurrences in 217 records.

(magnet* NEAR flow AND magnet* NEAR change): 4 records.

((((((indicat* NEAR flow AND indicat* NEAR change) AND (sens* NEAR flow AND sens* NEAR change)) AND ((amorphous NEAR flow AND amorphous NEAR change) OR (nano-crystalline NEAR flow AND nano-crystalline NEAR change))) AND (bias NEAR flow AND bias NEAR change)) AND (magnet* NEAR flow AND magnet* NEAR change)): 0 records.

magnetic NEAR flow: 228 occurrences in 179 records.

magnetic NEAR change: 196 occurrences in 158 records.

(magnetic NEAR flow AND magnetic NEAR change): 3 records.

(((((((indicat* NEAR flow AND indicat* NEAR change) AND (sens* NEAR flow AND sens* NEAR change)) AND ((amorphous NEAR flow AND amorphous NEAR change) OR (nano-crystalline NEAR flow AND nano-crystalline NEAR change))) AND (bias NEAR flow AND bias NEAR change)) AND (magnet* NEAR flow AND magnet* NEAR

change)) AND (magnetic NEAR flow AND magnetic NEAR change)): 0 records.

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Query :

`(("nano-crystalline" or amorphous)) <A`

Query: ((**"nano-crystalline"** or amorphous)) <AND> (((sens* and magnetic and field and chang*) <in> title) <AND> ((coil and inductance and change)) <in> abstract) <AND> ((free or cantilevered or hang*)) <in> claims)

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